Spin-Orbit-Torque Switching Mediated by an Antiferromagnetic Insulator
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Spin-Orbit Torque Switching Mediated by an Antiferromagnetic Insulator

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Abstract

We report the observation of antiferromagnetic insulator mediated spin-orbit torque switching in Pt/NiO/Co$_{1-x}$Tb$_x$ heterostructures. By measuring the current-induced shift in the magnetic hysteresis loops and the second-harmonic anomalous Hall resistance, we quantitatively determined the spin-orbit torque efficiency in Pt/NiO/Co$_{1-x}$Tb$_x$ samples with different NiO thicknesses, uncovering a systematic evolution of the magnetic switching behavior. The measured spin-orbit torque efficiency is enhanced in the low NiO thickness regime (1 ~ 2 nm), highlighting the efficient spin manipulation across a disordered antiferromagnetic insulator.
I. INTRODUCTION

Spin transport and magnetic dynamics in antiferromagnetic (AF) insulators have recently attracted wide research interests [1-7]. Contrary to the popular belief of AF materials being an inactive element for spin transport, recent experiments based on spin pumping [8, 9], spin torque ferromagnetic resonance [10], non-local spin transport [11, 12], and spin Seebeck effect [13-15] suggested efficient spin current transmission can be realized in various antiferromagnetic systems, via the mediation of AF exchange interactions. The large spin conductivity and the absence of charge conduction channels make AF insulators highly attractive for low power spintronic applications. Particularly, by using AF insulators as an insertion barrier in magnetic devices based on spin-orbit torque (SOT), one can potentially eliminate the shunting currents inside the free layer and minimize Joule heating [16]. In this work, we show initial experimental evidence towards this direction. Specifically, we utilized the current-induced SOT [17-19] in a Pt layer to switch a Co_{1-x}Tb_x free layer across a thin AF insulator NiO. In the ultrathin spacer thickness regime (1~ 2 nm), we even observed an enhancement of the SOT efficiency compared with a Pt/Co_{1-x}Tb_x bilayer. The realization of magnetic switching in Pt/NiO/Co_{1-x}Tb_x heterostructures provides proof of AF insulator mediated SOT, enabling promising material platforms and device structures for energy favorable spin manipulation.

II. CHARACTERIZATION OF MAGNETIC PROPERTIES

Current-induced SOT has been proven to be an efficient mechanism for magnetic moment reorientation [17-21]. In typical device structures, a clean, transparent interface between the SOT material and the magnetic electrode is critical to ensure a high transmission rate for spins. To verify whether the presence of an AF insulator barrier allows for the transmission of spin torque, we deposited Pt(5 nm)/NiO(0.5-10 nm)/Co_{1-x}Tb_x(4-10 nm)/SiN_x(5 nm) multilayers
on oxidized Si substrates using magnetron sputtering. The different Co$_{1-x}$Tb$_x$ film thicknesses were chosen for optimal perpendicular magnetic anisotropy. The schematic of the film stacks is shown in Fig. 1(a), where the Pt layer acts as a spin current source and SiN$_x$ is used as an insulating capping layer to avoid oxidation of the magnetic film. Co$_{1-x}$Tb$_x$ was chosen as the magnetic free layer because it can be deposited on a variety of underlayers and substrates while maintaining a robust PMA [22-28]. In our experiment, Co$_{1-x}$Tb$_x$ (CoTb in short for the rest of the work) with different chemical compositions were tested. We concluded that a Tb atomic ratio of $x = 0.23$ was optimal for achieving a square magnetic hysteresis loop. Figure 1(b) shows the results from vibrating-sample magnetometry (VSM) measurements, from which an effective out-of-plane anisotropy field $H_K \sim 6000 \text{ Oe}$ was determined. The devices were patterned into micrometer-size Hall bar structures by standard photolithography and lift-off processes [Fig. 1(c)], with a channel width of 10 $\mu\text{m}$. The anomalous Hall resistance $R_H$ of a fabricated device as a function of applied out-of-plane magnetic field $H_z$ is plotted in Fig. 1(d). The measured anomalous Hall resistance $R_H$ is $0.3 \Omega$, while the coercivity is $\sim 600 \text{ Oe}$, in agreement with the VSM results. All of the measurements reported in this letter were performed at room temperature.

III. SPIN-ORBIT TORQUE INDUCED MAGNETIC SWITCHING

As shown in Fig. 1(a), when an electrical charge current $J_c$ flows through the Pt layer along the $x$-direction, a spin current will be generated along the $z$-axis with spin polarization $\sigma$ oriented along the $y$-axis by spin Hall effect, which will transport across the insulating NiO layer [29, 30]. To check whether the spin current absorbed by the CoTb free layer $J_s$ exerts any influence on its magnetic moment, we carried out current-induced magnetic switching measurements on a series of Hall bar devices. Results from Pt/NiO($t_{\text{NiO}}$)/CoTb/SiN$_x$ samples with the NiO thickness $t_{\text{NiO}}$ varying between 0 and 5 nm are shown in Fig. 2(a) ~ (e). In these
measurements, an external DC magnetic field of $H_x = \pm 200$ Oe was applied along the current direction to give a deterministic switching polarity [17, 31]. We applied millisecond current pulses $J_{\text{pulse}}$ to minimize Joule heating. The anomalous Hall resistance was measured with a lower sensing current ($\sim 0.5$ mA) after each applied pulse. As expected, in the absence of the NiO layer [Fig. 2(a)], the CoTb magnetization reversibly switches between $+z$ and $-z$ directions under positive and negative applied current. The switching curves change polarity when the external DC magnetic field $H_x$ is reversed, consistent with the mechanism of SOT-induced magnetic switching. With the insertion of a thin NiO layer between the Pt and CoTb layer, SOT-induced magnetic switching features still remain when the NiO thickness is smaller than 5 nm [Fig. 2(b)-2(d)]. In particular, for the samples with 0.5 and 1 nm thick NiO spacer, the magnitude of the switching current is similar to that of the Pt/CoTb sample, indicating a high transmission of the spin current. Meanwhile, for NiO spacer thickness equal to or larger than 5 nm, no magnetic switching behavior was observed [Fig. 2(e)]. By comparing the $R_H$ change in the current-induced switching experiment with that from field switching experiments of Fig. 1(d), we determined that the portion of flipped magnetic domains during switching is 80% ~ 50% in Fig. 2(a) ~ 2(c) and 5% in Fig. 2(d). The decrease in the switching ratio of the 2 nm sample and the disappearance of magnetic switching in the 5 nm sample can be explained by spin memory loss [32] in the NiO layer due to defects and/or inhomogeneities in the thin film heterostructures.

In addition to NiO, it was recently reported that Fe$_2$O$_3$ also possesses antiferromagnetic ordering and supports spin current transport [12]. Therefore, we also performed the SOT-induced switching measurements in Pt/Fe$_2$O$_3$(1 nm)/CoTb heterostructures as shown in Fig. 2(f). Clear magnetic switching features can be observed. To confirm that the observed magnetic switching in Pt/NiO/CoTb and Pt/Fe$_2$O$_3$/CoTb samples are related to the AF ordering of the employed
insulators, we performed a control experiment by inserting a 1 nm diamagnetic MgO layer between Pt and CoTb. As shown in Fig. 2(f), no magnetic switching was observed in the control sample, which is in sharp contrast with results obtained in the AF-insulator-based heterostructures. This unambiguously demonstrates the significant role played by the AF insulator in achieving efficient magnetic control in these samples.

IV. QUANTITATIVE DETERMINATION OF SPIN-ORBIT TORQUE EFFICIENCY

The threshold current of multi-domain samples is influenced by extrinsic factors such as domain wall depinning field and the applied in-plane field. Therefore, in general it is difficult to precisely determine the SOT efficiency from the magnitude of the switching current. To quantitatively measure SOT efficiencies in the series of Pt/NiO(\(t_{NiO}\))/CoTb samples, we utilized two independent experimental techniques: measurement on the current-induced hysteresis loop shift of \(R_H-H_z\) curve and second-harmonic measurement of the anomalous Hall resistance. In the first approach, we applied an in-plane bias field \(H_x\) along the current direction and measured the horizontal shift of the \(R_H-H_z\) loops induced by the damping-like term of the effective SOT field \(H_z^{\text{eff}}\) [33]. Figure 3(a) and 3(b) show the field induced magnetic switching curves for Pt(5 nm)/NiO(1 nm)/CoTb(5 nm) sample under \(H_x = \pm 300\) Oe respectively. It is noted that the center of the \(R_H - H_z\) curve shifts to the positive (negative) direction in the presence of a positive (negative) 10 mA current. When the in-plane field reverses, the shift of the magnetic hysteresis loop changes direction, which is consistent with the expected magnetic domain wall chirality change under a magnetic field. We further measured the \(R_H - H_z\) hysteresis loops under a series of applied currents with \(H_x = 0, \pm 200,\) and \(\pm 300\) Oe. As shown in Fig. 3(c), for each different in-plane field, \(H_z^{\text{eff}}\) scales linearly with the applied current. The dependence of \(H_z^{\text{eff}}\) on \(H_x\) for a fixed applied current density of \(J_c = 1.5 \times 10^7\) A/cm\(^2\) is summarized in Fig. 3(d). The increase of
$H_z^{\text{eff}}$ with the applied in-plane field is related to the Dzyaloshinskii-Moriya interaction (DMI) at the interface between the magnetic layer (CoTb) and the neighboring layers, which can create stable Néel type domain walls with a certain type of chirality [22, 34]. For $H_x = 0$, domain walls do not have a preference for magnetic switching, leading to zero effective field $H_z^{\text{eff}}$. As $H_x$ increases and starts to overcome the effective DMI field, domain walls start to move in the direction that favors magnetic switching [20, 21, 34-36]. Due to the limit on the maximum $H_x$ that can be reached by our vector field electromagnet system, we did not observe the expected saturation of $H_z^{\text{eff}}$. Here, we use the measured $H_z^{\text{eff}}$ under the maximum bias field $H_x = \pm 300$ Oe to provide a lower bound estimation on the SOT efficiency characterized by $J_s/J_c$, which can be calculated with materials parameters using the formula [33, 37]:

$$J_s = \frac{2e\mu_0M_SH_z^{\text{eff}}t_{\text{CoTb}}}{\pi J_c h}$$

(1)

where $e$ is the electron charge, $\mu_0$ is the vacuum permeability, $M_S$ is the saturated magnetization, $t_{\text{CoTb}}$ is the thickness of the CoTb layer, $J_c$ is the electrical current density flowing through Pt layer after considering the electrical shunting effect of CoTb, and $h$ is the reduced Planck’s constant. For $t_{\text{NiO}} = 1$ and 2 nm, the obtained $J_s/J_c$ in Pt/NiO($t_{\text{NiO}}$)/CoTb samples are determined to be $0.051 \pm 0.005$ and $0.034 \pm 0.003$ respectively, which are larger than $J_s/J_c = 0.017 \pm 0.002$ measured in the Pt/CoTb bilayer structure without a NiO insertion.

The second experimental approach that we employed to calibrate the effective field is the second-harmonic measurement of the anomalous Hall resistance [38-42]. When applying an alternating current (AC) through the device, an alternating field $H_z^{\text{eff}}$ proportional to $\sigma \times m$ generated from the spin Hall effect in the Pt film can cause the CoTb magnetization $m$ to oscillate around the equilibrium position, giving rise to a second-harmonic anomalous Hall
resistance $R_{2\omega}$. Because only one external magnetic field is required for this experiment, we can apply a larger field $H_x$ along the current direction to overcome the magnetic anisotropy field $H_K$. In the regime where $|H_x| > H_K$, the observed second-harmonic anomalous Hall resistance can be simplified to the following formula [40, 41],

$$R_{2\omega} = \frac{1}{2} \frac{R_H H_{\text{eff}}}{(|H_x| - H_K)}$$  \hspace{1cm} (2)

The amplitude of the AC current is 5 mA with a frequency of $f = 160$ Hz. Figure 4(a) shows the measured $R_{2\omega}$ as a function of the external in-plane field $H_x$ for Pt/NiO(1 nm)/CoTb sample. In the large in-plane field regime ($|H_x| > H_K$), the measured $R_{2\omega}$ scales well with $1/(|H_x| - H_K)$ for $t_{\text{NiO}} = 0.5, 1, \text{and } 2$ nm as shown by the gray fitting curves in Fig. 4(b). Here, we can exclude the small contribution from the planar Hall effect and the anomalous Nernst effect via the exhibited field and in-plane angular dependence of the measured $R_{2\omega}$ [43]. Utilizing the fitted $H_{\text{eff}}$ and equation (1), we can determine the SOT efficiency $J_s/J_c$ to be $0.088 \pm 0.009$ and $0.076 \pm 0.008$ for $t_{\text{NiO}} = 1$ and 2 nm respectively, which is higher than the value of Pt/CoTb bilayer structure.

The evolution of $J_s/J_c$ with NiO spacer thickness $t_{\text{NiO}}$ measured by both experimental approaches are summarized in Fig. 4(c). As mentioned above, $J_s/J_c$ measured by the shift of magnetic hysteresis loop is limited by the unsaturated $H_{\text{eff}}$ under a small in-plane bias field, which represents a lower bound estimation for the real charge-to-spin conversion efficiency. Despite this, $J_s/J_c$ values from the two experimental approaches show very similar trends: they first increase and reach a maximum when $t_{\text{NiO}} = 1$ nm. As the NiO thickness increases further, $J_s/J_c$ starts to decay and finally becomes negligibly small. The increase of spin torque efficiency with an ultrathin NiO insertion layer can be explained by an improved spin mixing conductance at Pt/NiO and NiO/CoTb interfaces, compared with a direct Pt/CoTb contact. It is worth to note
that our prepared NiO thin with thickness $t_{\text{NiO}}$ of 1 ~ 2 nm are disordered, they exhibit geometrical frustration instead of a long range antiferromagnetic ordering with a preferred magnetic orientation, therefore leading to a rapid relaxation of the injected spin currents as well as a short spin decay length compared with some of previous studies [10, 44-46]. While the short range magnetic fluctuation inside ultrathin NiO films allows for transparent transmission of magnon spin current, AF ordering gets restored with thicker NiO insertions ($t_{\text{NiO}} \geq 5$ nm) and the large magnon band gap prohibits the transmission of low energy spin current [47]. Although the observed enhancement in spin transmission efficiency in the low NiO thickness regime was also previously reported in inverse spin Hall effect studies [8, 14, 15], the robust magnetic switching features we show here unambiguously demonstrates the technical significance of spin torque transfer in AF insulators and paves the way toward the future energy favorable spintronic devices.

V. CONCLUSION

In conclusion, we report the observation of antiferromagnetic insulator mediated spin-orbit torque magnetic switching in a series of Pt/NiO/CoTb samples, demonstrating the optimal interfacial conditions and a large spin transport efficiency. By measuring the current induced shift of the magnetic hysteresis loops and the second-harmonic anomalous Hall resistance, we determined the spin torque efficiency and observed an enhancement in the charge-to-spin conversion ratio with the insertion of an ultrathin NiO layer. Our results highlight the significant role played by an antiferromagnetic insulator in achieving energy favorable magnetic control and suggest a new path toward next generation magnetic switching devices.

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Figure captions:

**Figure 1** (a) Schematic of SOT in Pt/NiO/CoTb heterostructures. The generated effective field $H_{SO}$ is proportional to $\sigma \times m$. (b) Room temperature in-plane and out-of-plane magnetic hysteresis loops of Pt(5 nm)/NiO(1 nm)/CoTb(5 nm) sample measured by vibrating sample magnetometry. (c) Image of a patterned Pt(5 nm)/NiO(1 nm)/CoTb(5 nm)/SiNx(3 nm) Hall bar device with an illustration of the SOT induced magnetic switching measurement setup. The current is applied along the x-axis and the anomalous Hall voltage is detected in the y-direction. (d) The measured anomalous Hall resistance of Pt(5 nm)/NiO(1 nm)/CoTb(5 nm) Hall bar device as a function of out-of-plane magnetic field $H_z$.

**Figure 2** (a) ~ (e) SOT-induced magnetic switching curves under $\pm$ 200 Oe in-plane bias field $H_x$ of Pt/NiO($t_{NiO}$)/CoTb samples for $t_{NiO}$ = 0, 0.5, 1, 2, and 5 nm, separately. (f) Control measurements of Pt/Fe$_2$O$_3$(1 nm)/CoTb and Pt/MgO(1 nm)/CoTb samples. The data for Pt/MgO(1 nm)/CoTb sample is shifted vertically for clarity.

**Figure 3** Current-induced shift of anomalous Hall resistance loops of Pt/NiO(1 nm)/CoTb sample under bias field (a) $H_x$ =300 Oe and (b) $H_x$ = -300 Oe. The applied DC currents are $\pm$10 mA. (c) The measured $H_x^{eff}$ in Pt/NiO(1 nm)/CoTb sample as a function of current density $J_c$ under different bias fields $H_x$ = 0, $\pm$ 200, and $\pm$ 300 Oe. (d) The measured $H_x^{eff}$ as a function of the applied in-plane bias field $H_x$ at $J_c = 1.5 \times 10^7$ A/cm$^2$.

**Figure 4** (a) In-plane field dependence of the measured second-harmonic resistance of Pt/NiO(1 nm)/CoTb sample. The amplitude of the input AC current is 5 mA with a frequency $f = 160$ Hz. (b) The measured second-harmonic resistances of Pt/NiO($t_{NiO}$)/CoTb samples with $t_{NiO}$ = 0.5, 1, and 2 nm in the high field regime where $H_x \geq 6000$ Oe. The gray dash lines represent fitting
curves proportional $1/(|H_x| - H_K)$ when CoTb films are in a single domain state. (c) NiO spacer thickness dependence of the charge-to-spin conversion efficiency $J_s/J_c$ measured by the shift of magnetic hysteresis loops and second-harmonic resistance analysis methods in Pt/NiO/CoTb devices.
Figure 1
Figure 2
Figure 3
Figure 4